**Qualification Results Summary for**

**ADE7932/ADE7933 Die Revision**

|  |  |  |  |
| --- | --- | --- | --- |
| QUALIFICATION PLAN / STATUS | | | |
| **Test** | **Specification** | **Sample Size** | **Results** |
| High Temperature Operating Life (HTOL)\*2 | JEDEC *JESD22-A108* | **9 x 77** | **Pass** |
| Highly Accelerated Stress Test (HAST)\*1 | JEDEC*JESD22-A110* | **9 x 77** | **Pass** |
| Temperature Cycle (TC)\*1 | JEDEC*JESD22-A104* | **9 x 77** | **Pass** |
| Unbiased HAST\*1 | JEDEC *JESD22-A118* | **9 x 77** | **Pass** |
| High Temperature Storage Life (HTSL)1 | JEDEC*JESD22-A103* | **9 x 77** | **Pass** |
| Solder Heat Resistance  (SHR)\*1 | JEDEC/IPC *J-STD-020* | **1 x 30** | **Pass** |
| Latch-Up1 | JEDEC *JESD78* | **1 x 18** | **Pass** ±200mA @ +5.445V |
| Electrostatic Discharge  *Human Body Model1* | ESDA/JEDEC *JS-001* | **3/voltage** | **Pass** ±1000V |
| Electrostatic Discharge  *Field-Induced Charged Device Model1* | JEDEC *JS-002* | **3/voltage** | **Pass** ±1250V |

\*Preconditioned per JEDEC/IPC J-STD-020

1 Electrical test was performed at Room